## Search Notes



Application/Control No.

Applicant(s)/Patent Under Reexamination

PARAGIOS ET AL.

09944317

Examiner

Lavin, Christopher L

Art Unit 2624

Notes	Date	Examiner
Jpdated East Search	08/09/2006	CLL
Jpdated IEEE Search	08/08/2006	CLL
U.S. Patent and Trademark Office		Part of Paper No.:

## Interference Searched



Application/Control No.

Applicant(s)/Patent Under Reexamination

09944317

PARAGIOS ET AL.

Examiner

Lavin, Christopher L

Art Unit 2624

Class	SubClass	Date	Examiner
See Interference Search Printout			
U.S. Patent and Trademark Office		Part of Paper No.:	